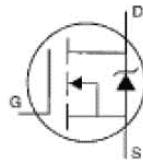
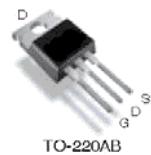


Dynamic dv/dt Rating  
 175 °C Operating Temperature  
 Fast Switching  
 Ease of Paralleling  
 Simple Drive Requirements



V<sub>DSS</sub>=60V  
 R<sub>DS(on)</sub>=0.20Ω  
 I<sub>D</sub>=10A



**G: Gate**  
**D: Drain**  
**S: Source**

### Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

### Absolute Maximum Ratings

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> =25	Continuous Drain Current, V <sub>GS</sub> @ 10V	10	A
I <sub>D</sub> @ T <sub>C</sub> =100	Continuous Drain Current, V <sub>GS</sub> @ 10V	7.2	
I <sub>DM</sub>	Pulsed Drain Current	40	
P <sub>D</sub> @ T <sub>C</sub> =25	Power Dissipation	43	W
	Linear Derating Factor	0.29	W/
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy	47	mJ
dv/dt	Peak Diode Recovery dv/dt	4.5	V/ns
T <sub>J</sub>	Operating Junction and Storage Temperature Range	-55 to +175	
T <sub>STG</sub>	Soldering Temperature, for 10 seconds	300 (1.8mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf·in (1.1N·m)	

### Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
R <sub>ejc</sub>	Junction-to-Case	-	-	3.5	/W
R <sub>eCS</sub>	Case-to-Sink, Flat, Greased Surface	-	0.50	-	
R <sub>eJA</sub>	Junction-to-Ambient	-	-	62	

### Electrical Characteristics @ T<sub>J</sub>=25 °C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	60	-	-	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
ΔV <sub>(BR)DSS/ΔT<sub>J</sub></sub>	Breakdown Voltage Temp. Coefficient	-	0.063	-	V/°C	Reference to 25 °C, I <sub>D</sub> =1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	-	-	0.20	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =6.0A
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	-	4.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA
g <sub>fs</sub>	Forward Transconductance	2.4	-	-	S	V <sub>DS</sub> =25V, I <sub>D</sub> =6.0A
I <sub>DSS</sub>	Drain-to-Source Leakage Current	-	-	25	μA	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V
		-	-	250		V <sub>DS</sub> =48V, V <sub>GS</sub> =0V, T <sub>J</sub> =150 °C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	-	-	100	nA	V <sub>GS</sub> =20V
	Gate-to-Source Reverse Leakage	-	-	-100		V <sub>GS</sub> =-20V
Q <sub>g</sub>	Total Gate Charge	-	-	11	nC	I <sub>D</sub> =10A
Q <sub>gs</sub>	Gate-to-Source Charge	-	-	3.1		V <sub>DS</sub> =48V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	-	-	5.8		V <sub>GS</sub> =10V See Fig. 6 and 13
t <sub>d(on)</sub>	Turn-On Delay Time	-	10	-	ns	V <sub>DD</sub> =30V
t <sub>r</sub>	Rise Time	-	50	-		I <sub>D</sub> =10A
t <sub>d(off)</sub>	Turn-Off Delay Time	-	13	-		R <sub>G</sub> =24Ω
t <sub>f</sub>	Fall Time	-	19	-		R <sub>D</sub> =2.7Ω See Figure 10
L <sub>D</sub>	Internal Drain Inductance	-	4.5	-	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L <sub>S</sub>	Internal Source Inductance	-	7.5	-		
C <sub>iss</sub>	Input Capacitance	-	300	-	pF	V <sub>GS</sub> =0V
C <sub>oss</sub>	Output Capacitance	-	160	-		V <sub>DS</sub> =25V
C <sub>rss</sub>	Reverse Transfer Capacitance	-	29	-		F=1.0MHz See Figure 5

### Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	-	-	10	A	MOSFET symbol showing the integral reverse p-n junction diode
I <sub>SM</sub>	Pulsed Source Current (Body Diode)	-	-	40		
V <sub>SD</sub>	Diode Forward Voltage	-	-	1.6	V	T <sub>J</sub> =25 , I <sub>S</sub> =10A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	-	70	140	ns	T <sub>J</sub> =25 , IF=10A
Q <sub>rr</sub>	Reverse Recovery Charge	-	0.20	0.40	μC	di/dt=100A/μs
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

**Notes:**

Repetitive rating: pulse width limited by max. junction temperature (See Figure 11)

I<sub>SD</sub>≤10A, di/dt ≤ 90A/μs, V<sub>DD</sub>≤V<sub>(BR)DSS</sub>, T<sub>J</sub>≤175

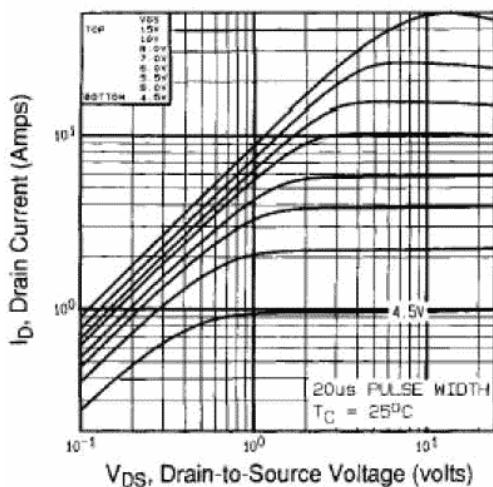


Fig 1. Typical Output Characteristics,  
T<sub>c</sub>=25

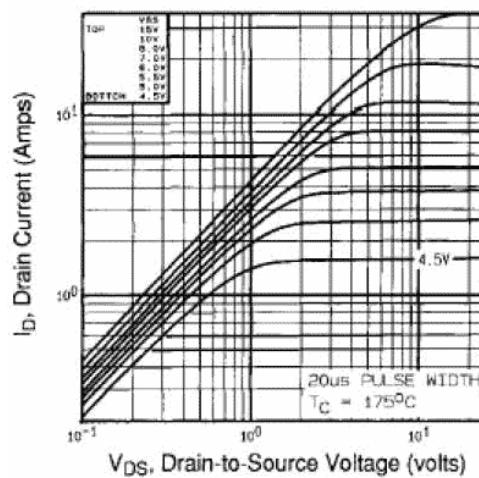


Fig 2. Typical Output Characteristics,  
T<sub>c</sub>=175

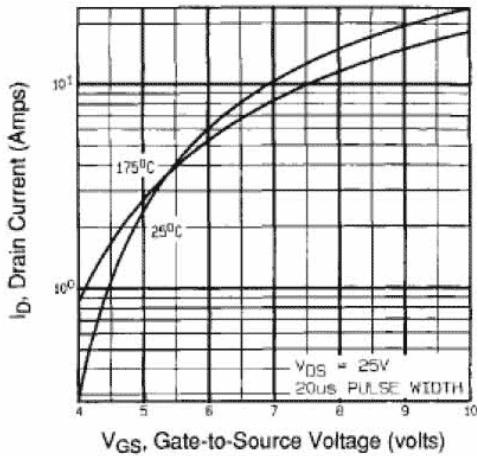


Fig 3. Typical Transfer Characteristics

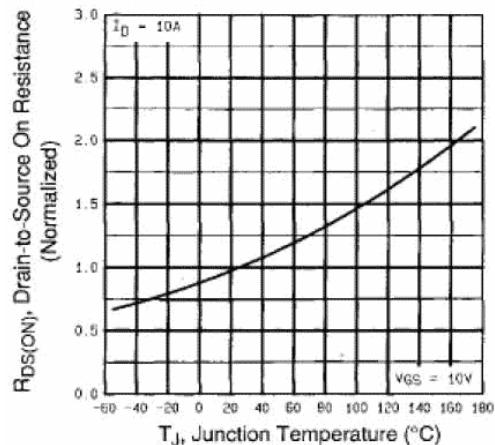


Fig 4. Normalized On-Resistance  
Vs. Temperature

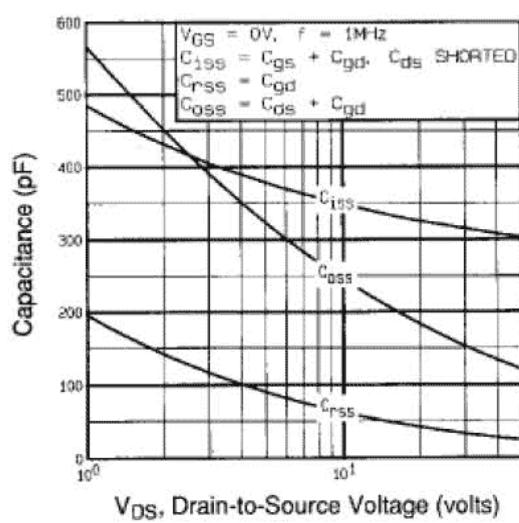


Fig 5. Typical Capacitance Vs.  
Drain-to-Source Voltage

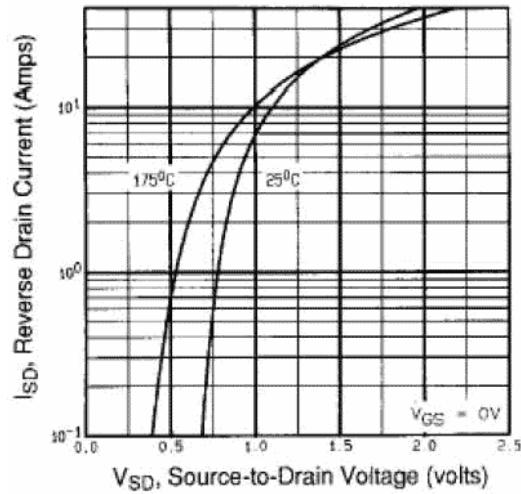


Fig 7. Typical Source-Drain Diode  
Forward Voltage

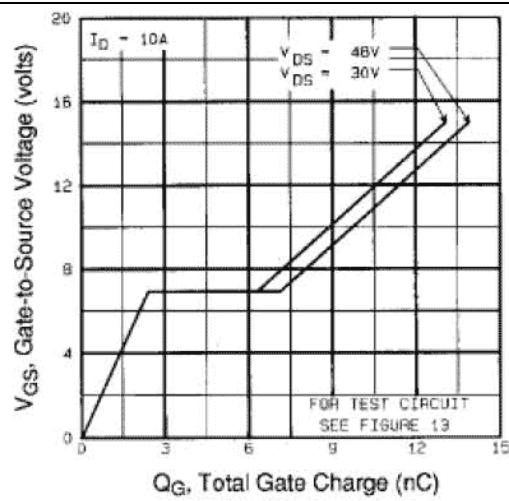


Fig 6. Typical Gate Charge Vs.  
Gate-to-Source Voltage

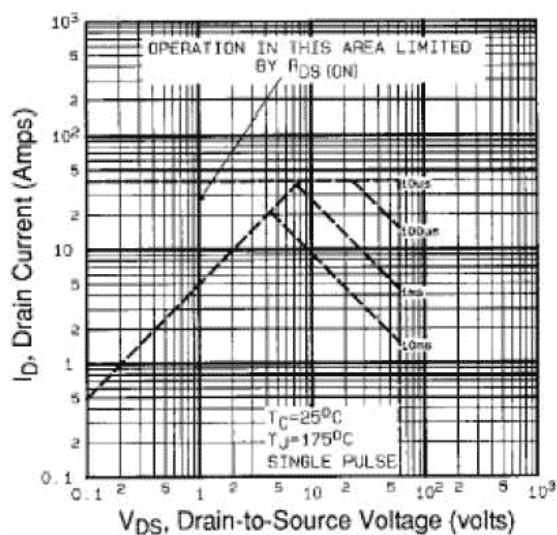


Fig 8. Maximum Safe Operating Area

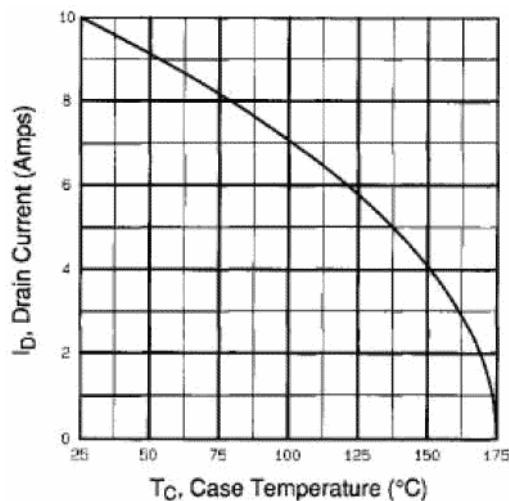


Fig 9. Maximum Drain Current Vs.  
Case Temperature

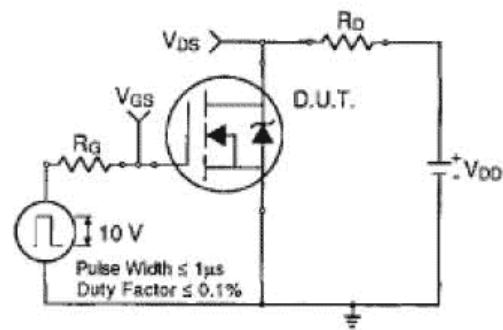


Fig 10a. Switching Time Test Circuit

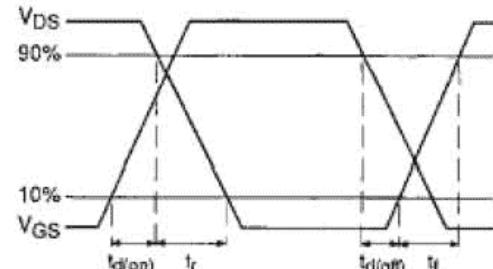


Fig 10b. Switching Time Waveforms

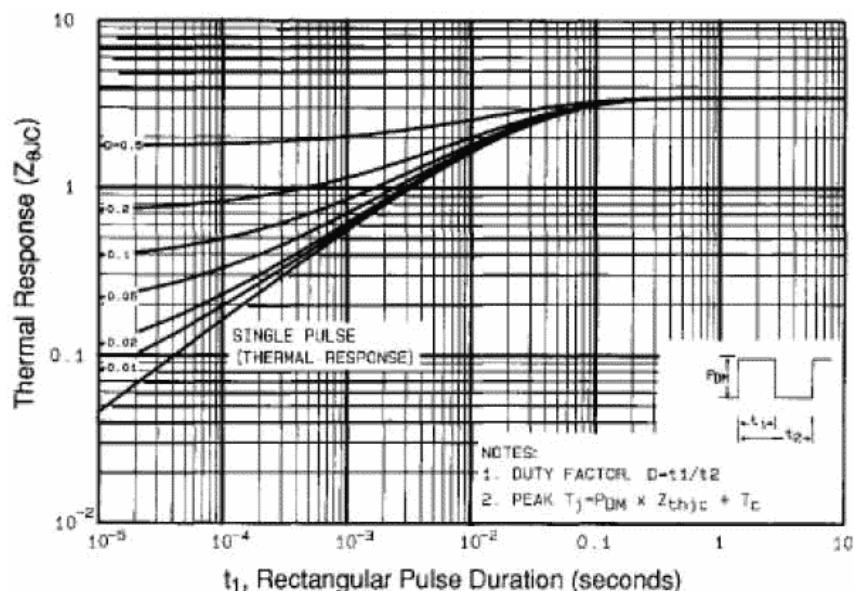


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

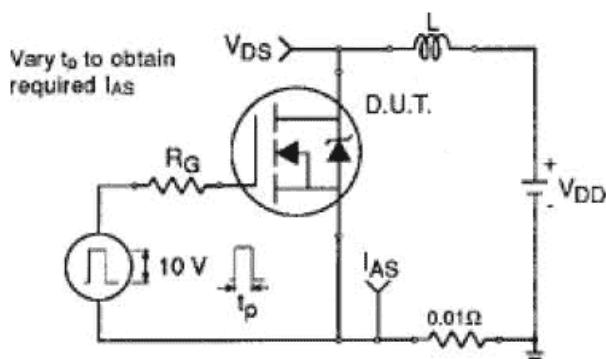


Fig 12a. Unclamped Inductive Test Circuit

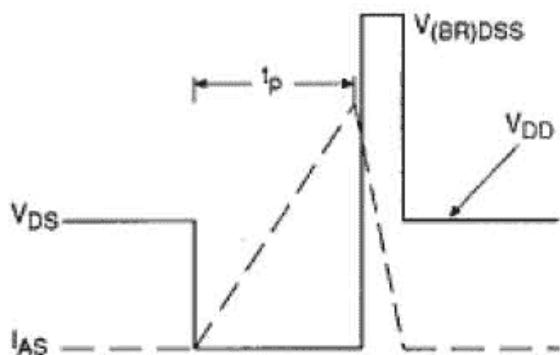


Fig 12b. Unclamped Inductive Waveforms

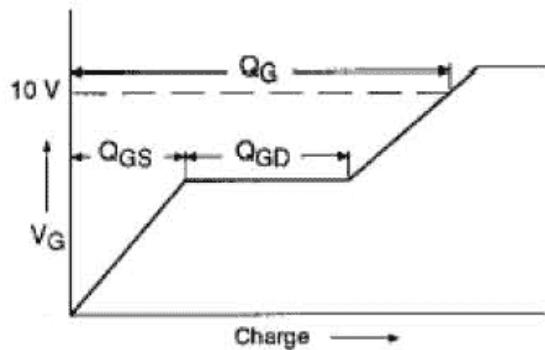


Fig 13a. Basic Gate Charge Waveform

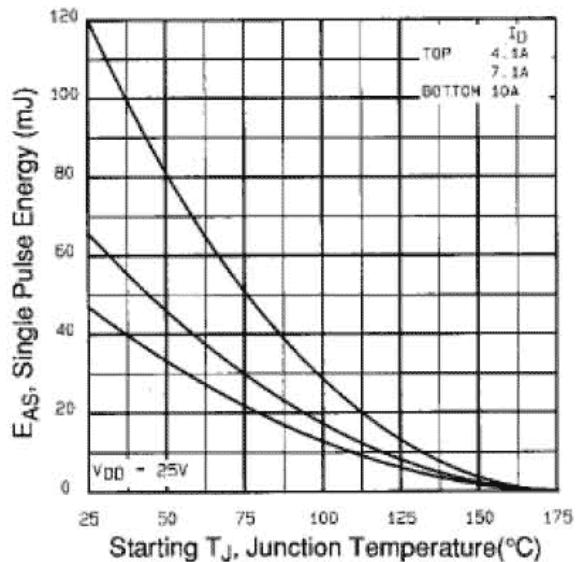
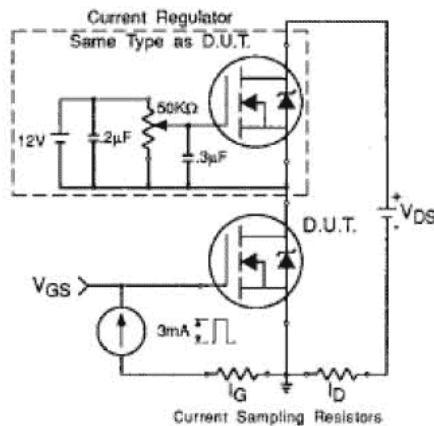
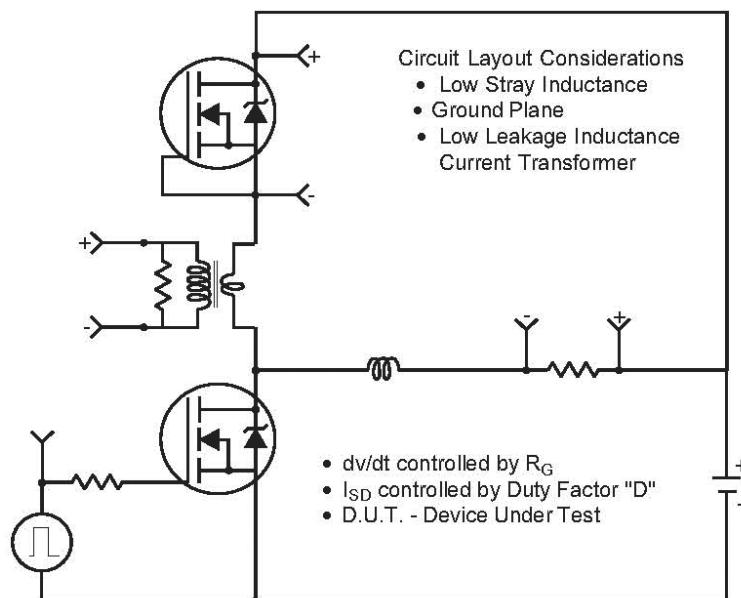
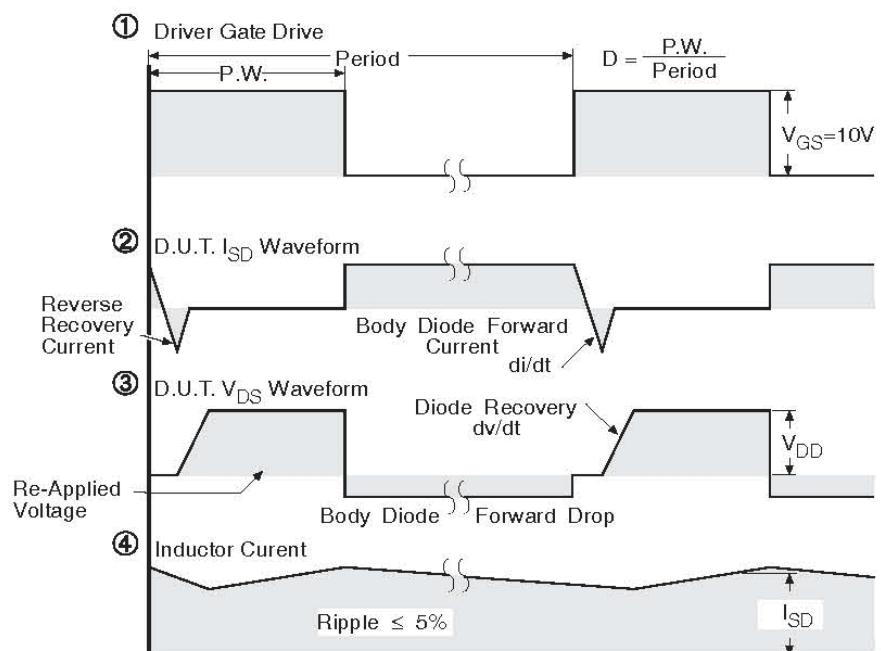

 Fig 12c. Maximum Avalanche Energy  
 Vs. Drain Current


Fig 13b. Gate Charge Test Circuit

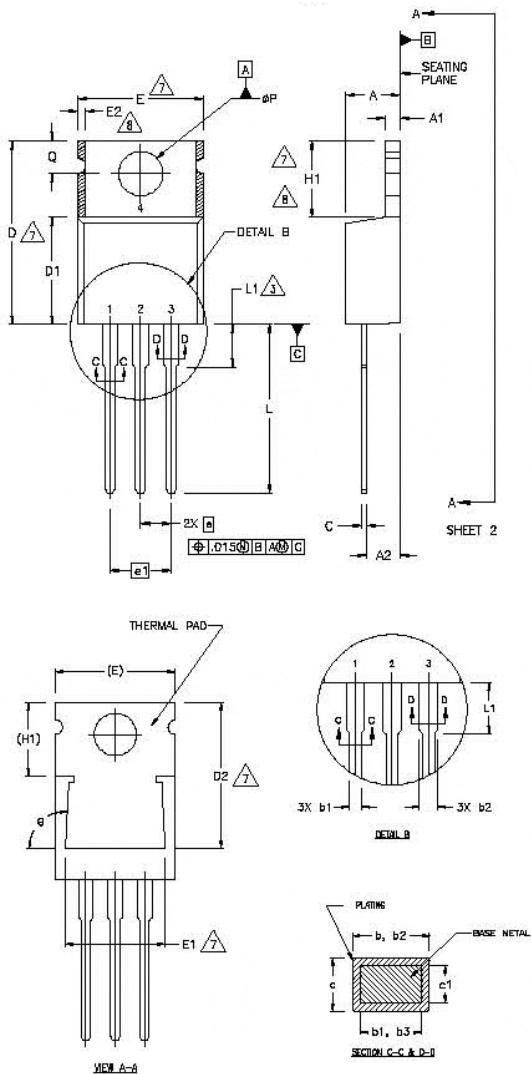
**Peak Diode Recovery dv/dt Test Circuit**


\* Reverse Polarity for P-Channel

\*\* Use P-Channel Driver for P-Channel Measurements


 \*\*\*  $V_{GS} = 5.0V$  for Logic Level and 3V Drive Devices

## TO-220AB Package Outline (Dimensions are shown in millimeters (inches))



## NOTES:

- 1 DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- 2 DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
- 3 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
- 4 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5 DIMENSION b1 & c1 APPLY TO BASE METAL ONLY.
- 6 CONTROLLING DIMENSION : INCHES.
- 7 THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- 8 DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRRREGULARITIES ARE ALLOWED.

## LEAD ASSIGNMENTS

## HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE

## IGETs, CoPACK

- 1.- GATE
- 2.- COLLECTOR
- 3.- Emitter

## DIODES

- 1.- ANODE/OPEN
- 2.- CATHODE
- 3.- ANODE

SYMBOL	DIMENSIONS				NOTES	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	3.56	4.82	.140	.190		
A1	0.51	1.40	.020	.055		
A2	2.04	2.92	.080	.115		
b	0.38	1.01	.015	.040		
b1	0.38	0.98	.015	.038	5	
b2	1.15	1.77	.045	.070		
b3	1.15	1.73	.045	.068		
c	0.36	0.61	.014	.024		
c1	0.36	0.56	.014	.022	5	
D	14.22	16.51	.560	.650	4	
D1	8.38	9.02	.330	.355		
D2	12.19	12.88	.480	.507	7	
E	9.66	10.66	.380	.420	4,7	
E1	8.38	8.89	.330	.350	7	
e	2.54 BSC		.100 BSC			
e1	5.08		.200 BSC			
H1	5.85	6.55	.230	.270		
L	12.70	14.73	.500	.580		
L1	—	6.35	—	.250		
ØP	3.54	4.08	.139	.161		
Q	2.54	3.42	.100	.135		
Ø	90°-93°		90°-93°			